

# **MOSFET** - Power, Single, N-Channel

80 V, 21.1 m $\Omega$ , 33 A

## **NVTFS6H860N**

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NVTFS6H860NWF Wettable Flanks Product
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	80	V
Gate-to-Source Voltage	€		V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	30	Α
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)	Steady	T <sub>C</sub> = 100°C		21	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	46	W
R <sub>θJC</sub> (Notes 1, 2, 3)		T <sub>C</sub> = 100°C		23	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	8.0	Α
Current R <sub>0JA</sub> (Notes 1, 3, 4)	Steady	T <sub>A</sub> = 100°C		5.5	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.1	W
R <sub>θJA</sub> (Notes 1, 3)		T <sub>A</sub> = 100°C		1.6	
Pulsed Drain Current	$T_A = 25^\circ$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	119	Α
Operating Junction and Range	Operating Junction and Storage Temperature Range			-55 to +175	°C
Source Current (Body Diode)			IS	38	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 1.5 A)			E <sub>AS</sub>	138	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

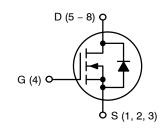
#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	3.3	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	48.2	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> MAX	I <sub>D</sub> MAX
80 V	21.1 mΩ @ 10 V	33 A

#### N-Channel



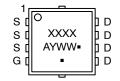


WDFN8 3.3x3.3, 0.65P CASE 511AB



WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)
CASE 515AN

#### **MARKING DIAGRAM**



XXXX = Specific Device Code A = Assembly Location

Y = Year
WW = Work Week
= Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	-	-			-	-	-
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> =	= 250 μA	80			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $T_{J} = 25^{\circ}\text{C}$				10	μΑ
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 30 μΑ	2.0		4.0	V
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I	<sub>D</sub> = 5 A		17.3	21.1	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>E</sub>	<sub>0</sub> = 10 A		41		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>iss</sub>				510		pF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, f = V <sub>DS</sub> = 40	1.0 MHz, ) V		78		1
Reverse Transfer Capacitance	C <sub>rss</sub>	VDS - 40 V			4.2		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10 A			1.8		nC
Gate-to-Source Charge	$Q_{GS}$				2.8		1
Gate-to-Drain Charge	$Q_{GD}$				1.6		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10 A			8.7		nC
SWITCHING CHARACTERISTICS (No	te 6)						
Turn-On Delay Time	t <sub>d(on)</sub>				8.0		ns
Rise Time	t <sub>r</sub>	$V_{GS} = 6.0 \text{ V}, V_{D}$	s = 64 V.		14		
Turn-Off Delay Time	t <sub>d(off)</sub>	I <sub>D</sub> = 10			18		
Fall Time	t <sub>f</sub>	1			5.0		1
DRAIN-SOURCE DIODE CHARACTEF	RISTICS				•	•	•
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.8	1.2	V
			T <sub>J</sub> = 125°C		0.7		1
Reverse Recovery Time	t <sub>RR</sub>				29		ns
Charge Time	t <sub>a</sub>	$V_{GS} = 0 \text{ V, } dl_S/dt = 100 \text{ A/}\mu\text{s,}$ $l_S = 10 \text{ A}$			20		
Discharge Time	t <sub>b</sub>				9.0		
Reverse Recovery Charge	Q <sub>RR</sub>				24		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.

6. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

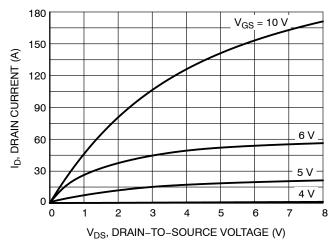


Figure 1. On-Region Characteristics

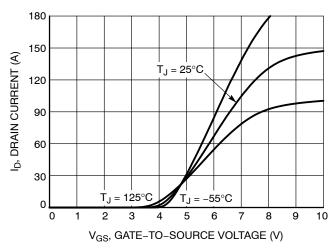


Figure 2. Transfer Characteristics

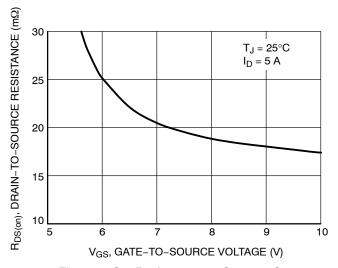


Figure 3. On-Resistance vs. Gate-to-Source Voltage

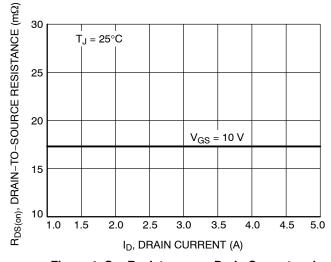


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

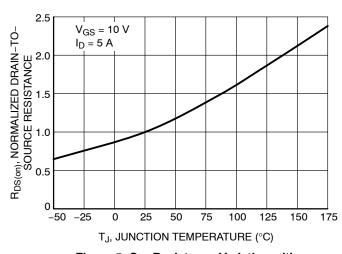


Figure 5. On–Resistance Variation with Temperature

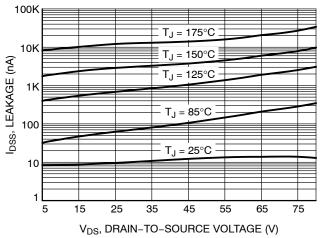


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

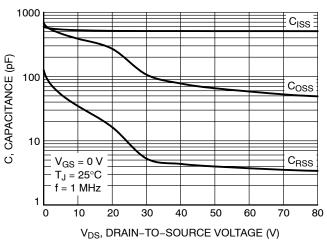


Figure 7. Capacitance Variation

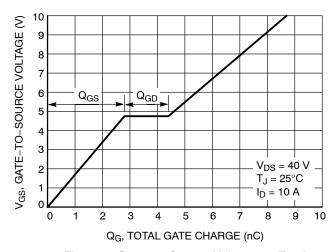


Figure 8. Gate-to-Source Voltage vs. Total Charge

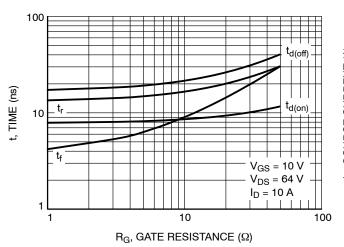


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

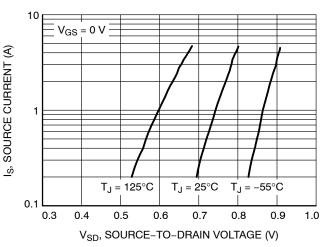


Figure 10. Diode Forward Voltage vs. Current

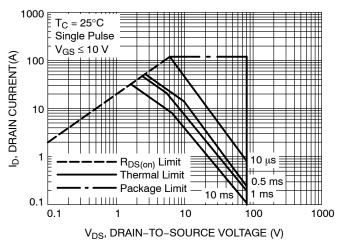


Figure 11. Maximum Rated Forward Biased Safe Operating Area

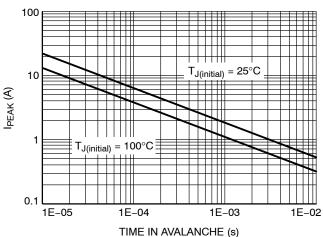


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

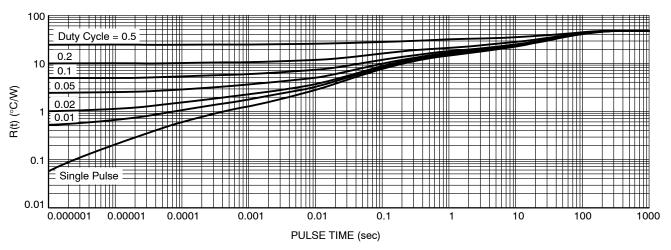


Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

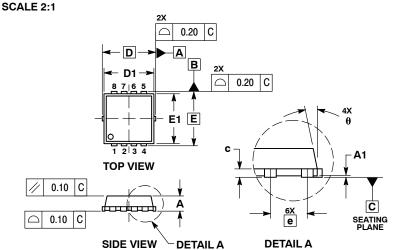
Device	Marking	Package	Shipping <sup>†</sup>
NVTFS6H860NTAG	860N	WDFN8 3.3x3.3, 0.65P (Pb-Free)	1500 / Tape & Reel
NVTFS6H860NWFTAG	60NW	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

**DATE 23 APR 2012** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
  PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		0	.130 BSC	;
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
E		3.30 BSC		0	.130 BSC	;
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е	0.65 BSC			(	0.026 BS	0
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
М	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °



#### **GENERIC MARKING DIAGRAM\***

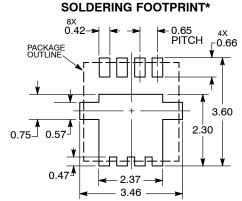


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

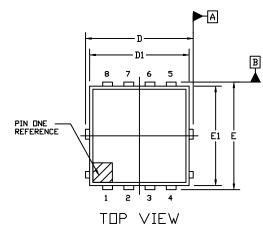
\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 1 OF 1	

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**DATE 25 AUG 2020** 



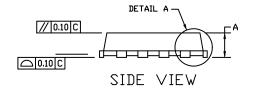


#### NDTES:

- 1. DIMENSIONING AND TOLERANCING PER.ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

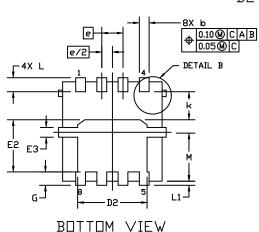
	PLATED AREA
DETAIL	C C SEATING PLANE

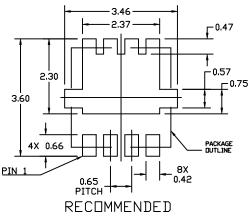
	MILLIMETERS			
DIM	MIN.	NDM.	MAX.	
A	0.70	0.75	0.80	
A1	0.00		0.05	
b	0.23	0.30	0.40	
n	0.15	0.20	0.25	
D	3.05	3.30	3.55	
D1	2.95	3.05	3.15	
D2	1.98	2.11	2.24	
Ε	3.05	3.30	3.55	
E1	2.95	3.05	3.15	
E2	1.47	1.60	1.73	
E3	0.23	0.30	0.40	
a		0.65 BSC		
G	0.30	0.41	0.51	
K	0.65	0.80	0.95	
٦	0.30	0.43	0.59	
L1	0.06	0.13	0.20	
М	1.40	1.50	1.60	





DETAIL B





MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

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DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)		

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